Title (en)

X-RAY ANALYSIS DEVICE AND METHOD FOR OPTICAL AXIS ALIGNMENT THEREOF

Title (de)

RÖNTGENANALYSEVORRICHTUNG UND VERFAHREN ZUR AUSRICHTUNG DER OPTISCHEN ACHSE DERSELBEN

Title (fr)

DISPOSITIF D'ANALYSE À RAYONS X ET PROCÉDÉ D'ALIGNEMENT D'AXE OPTIQUE CORRESPONDANT

Publication

EP 3588068 A2 20200101 (EN)

Application

EP 19182236 A 20190625

Priority

JP 2018125106 A 20180629

Abstract (en)

To provide an X-ray analysis device and a method for optical axis alignment thereof by which measurement time is shortened and measurement cost may be reduced without optical axis alignment at each measurement using an analyzer. The X-ray analysis device includes a sample stage for supporting a sample, an N-dimensional detector, and an analyzer including analyzer crystals. A detection surface of the N-dimensional detector has first and second detection areas, a plurality of optical paths includes a first optical path that directly reaches the first detection area and a second optical path that reaches via the analyzer crystals, and the N-dimensional detector performs a measurement of the first optical path by X-ray detection of the first detection area, and performs a measurement of the second optical path by X-ray detection of the second detection area.

IPC 8 full level

G01N 23/20 (2018.01)

CPC (source: CN EP US)

G01N 23/20 (2013.01 - CN EP); **G01N 23/20008** (2013.01 - CN); **G01N 23/2055** (2013.01 - US); **G01N 23/207** (2013.01 - US); **G01T 1/36** (2013.01 - CN); G01N 23/20025 (2013.01 - US); G01N 2223/5015 (2013.01 - US); G21K 1/06 (2013.01 - EP)

Citation (applicant)

- US 6665372 B2 20031216 - BAHR DETLEF [DE], et al
- JP H0949811 A 19970218 - RIGAKU DENKI CO LTD

Designated contracting state (EPC)

AL AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO RS SE SI SK SM TR

Designated extension state (EPC)

BA ME

DOCDB simple family (publication)

EP 3588068 A2 20200101; **EP 3588068 A3 20200115**; **EP 3588068 B1 20201202**; CN 110726742 A 20200124; CN 110726742 B 20230512; JP 2020003415 A 20200109; JP 6871629 B2 20210512; US 10837923 B2 20201117; US 2020003708 A1 20200102

DOCDB simple family (application)

EP 19182236 A 20190625; CN 201910510399 A 20190613; JP 2018125106 A 20180629; US 201916452707 A 20190626